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# Side-Channel and Fault Attacks in Post-quantum Cryptography

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## **Message from the Guest Editors**

Dear Colleagues,

Post-quantum cryptography (PQC) is a research subject investigating public-key cryptographic algorithms that are believed to resist quantum attacks. On July 5, 2022, NIST announced the selected KEM and digital signature candidates to be standardized in their PQC standardization project. The need to securely implement PQC schemes will drastically increase in the coming years as many commercial products or open-source hardware/software have planned the transition to PQC solutions. In this Special Issue, we are particularly interested in discovering new side-channel and fault attacks against known PQC implementations and proposing more efficient and secure countermeasures.

Topics of interest include but are not limited to:

- Power and EM side-channel attacks on postquantum implementations
- Micro-architectural side-channel attacks on postquantum implementations
- Masked implementations in post-quantum cryptography
- Efficient constant-time post-quantum implementations
- Fault attacks and countermeasures in postquantum cryptography
- Attacks and countermeasures on Fully Homomorphic Encryption (FHE) implementations



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## **Message from the Editor-in-Chief**

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